

**IN THE UNITED STATES
PATENT AND TRADEMARK OFFICE**

Patent Application

Inventors(s): Stanley Pau
Donald Milan Tennant

Case: 13-16

Serial No.:

Group Art Unit: Not assigned yet

Filing Date:

Examiner: Not assigned yet

Title: Focusable and Steerable Micro-miniature X-ray Apparatus

**THE COMMISSIONER OF PATENTS AND TRADEMARKS
WASHINGTON, DC 20231**

SIR:

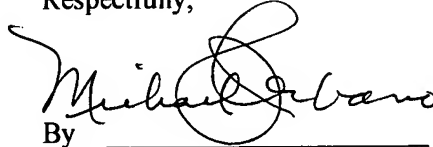
INFORMATION DISCLOSURE STATEMENT

In accordance with 37 CFR 1.97(b), the enclosed Information Disclosure Statement (IDS) is submitted for consideration in the above-identified application.

Copies of the reference(s) listed in the IDS are enclosed.

NO FEE IS REQUIRED.

Respectfully,



By

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Date: 11/18/03

Att. IDS with reference(s)

FORM PTO-1449 (REV. 1-84)	U.S. DEPARTMENT OF COMMERCE PATENT & TRADEMARK OFFICE	CASE NO. 13-16	SERIAL NO
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		APPLICANT: Stanley Pau et al.	
		FILING DATE	GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER							DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
	AA	4	3	4	0	2	8	3	7/82	Cohen	351	161	
	AB	5	6	2	8	6	5	9	5/97	Xie <i>et al.</i>	445	3	
	AC	6	1	4	8	0	6	1	11/00	Shefer <i>et al.</i>	378	121	
	AD	6	2	5	9	7	6	4	7/01	Evans-Lutterodt <i>et al.</i>	378	84	
	AE	6	4	4	8	1	0	0	9/02	Schulte <i>et al.</i>	438	20	
	AF	6	4	7	7	2	3	3	11/02	Ribbing <i>et al.</i>	378	136	
	AG	6	5	9	2	5	2	6	7/03	Lenker	600	463	
	AH												
	AI												
	AJ												
	AK												

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY/AUTHOR	CLASS	SUB- CLASS	TRANSL'N YES NO
AL							
AM							
AN							
AO							
AP							

OTHER (Including Author, Title, Date, Pertinent Pages, Etc.)

AR	Henke et al., Two-channel, elliptical..., Rev. Sci. Instrum., Vol. 56, No. 8, p. 1537 (Aug. 1985)
AS	Lee et al., High aspect ratio..., J. Vac. Sci. Tech., Vol. B12, No. 6, p. 3425 (Nov/Dec. 1994)
AT	Tang et al., Emission measurements..., J. Vac. Sci. Tech., Vol. B14, No. 6, p. 3455 (Nov/Dec. 1996)
AU	Nagao et al., Metal-oxide-semiconductor..., J. Vac. Sci. Tech., Vol. B21, No. 1, p. 495 (Jan/Feb. 2003)
AV	Busta et al., Characterization of electron..., J. Vac. Sci. Tech., Vol. B21, No. 1, p. 344 (Jan/Feb. 2003)
AW	Evans-Lutterodt et al., Single-element..., Optics Express, Vol. 11, No. 8, p. 919 (Apr. 2003)
AX	

EXAMINER:

DATE CONSIDERED:

SHEET 1 OF 1